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SEMICONDUCTOR®

FDB8896

N-Channel PowerTrench[®] MOSFET 30V, 93A, 5.7m Ω

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\text{DS}(\text{ON})}$ and fast switching speed.

Applications

DC/DC converters

GATE SOURCE TO-263AB FDB SERIES



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

		0 0				
Symbol	Parameter			Ratings	Units	
V _{DSS}	Drain to Sou	to Source Voltage			30	V
V _{GS}	Gate to Sou	rce Voltage			±20	V
	Drain Curre	Drain Current				
	Continuous (T _C = 25 ^o C, V _{GS} = 10V) (Note 1)				93	А
I _D	Continuous ($T_c = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1)				85	A
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 43^{\circ}C/W$)				19	A
	Pulsed			Figure 4	A	
E _{AS}	Single Pulse Avalanche Energy (Note 2)			74	mJ	
	Power dissipation			80	W	
PD	Derate above 25°C			0.53	W/ºC	
T _J , T _{STG}	Operating a	Dperating and Storage Temperature			-55 to 175	°C
Thermal _{R_{θJC}}	Charact	t eristics sistance Junction to C	Case TO-263		1.88	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient TO-263 (Note 3)				62	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient TO-263, 1in ² copper pad area 43				43	°C/W
Package		g and Orderin	•	1	Tono Width	Quantitu
Device M FDB8	•	FDB8896	TO-263AB	Reel Size 330mm	Tape Width 24mm	Quantity 800 units
FDBd	3890	FDB8896	TO-263AB	330mm	24000	800 units

- Features
- $r_{DS(ON)} = 5.7 m\Omega$, $V_{GS} = 10V$, $I_D = 35A$
- $r_{DS(ON)} = 6.8 m\Omega$, $V_{GS} = 4.5 V$, $I_D = 35 A$
- High performance trench technology for extremely low $r_{\mbox{DS}(\mbox{ON})}$
- · Low gate charge
- High power and current handling capability

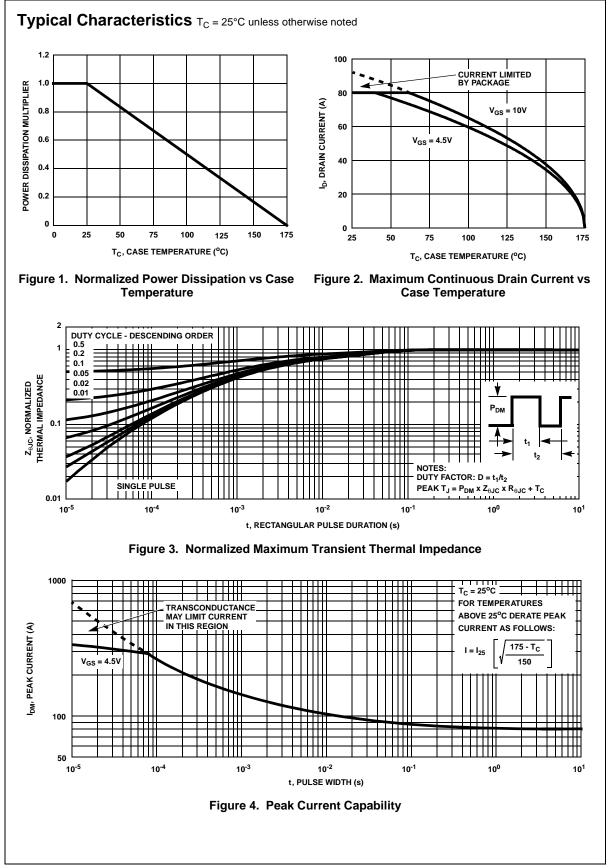
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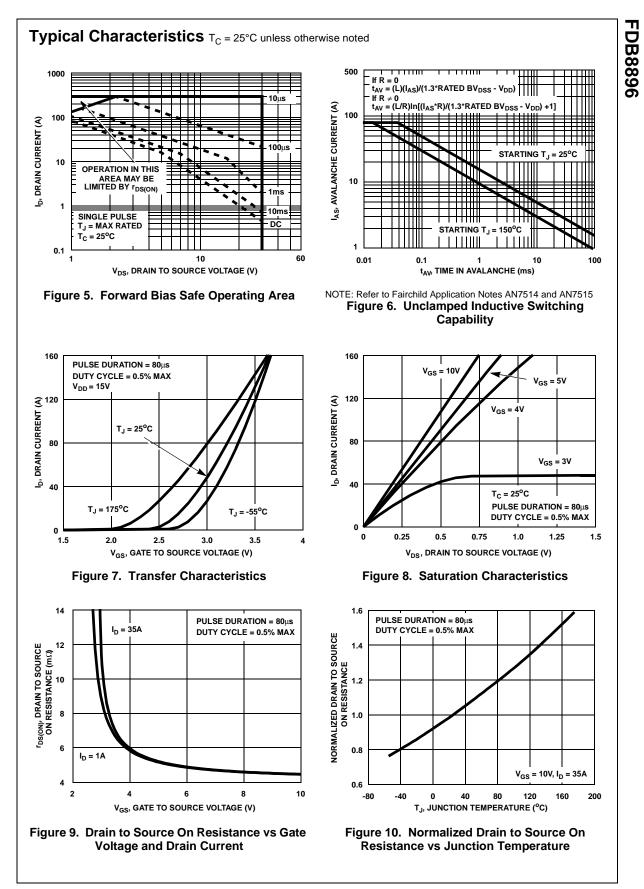
Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Chara	acteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} =	= 0V	30	-	-	V
	-	$V_{DS} = 24V$		-	-	1	
IDSS	Zero Gate Voltage Drain Current	50	T _C = 150°C	-	-	250	μA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V		-	-	±100	nA
On Chara	acteristics						
V _{GS(TH)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250μA		1.2	-	2.5	V
		I _D = 35A, V _{GS} = 10V		-	0.0049	0.0057	
r	Drain to Source On Resistance	I _D = 35A, V _{GS} = 4	I _D = 35A, V _{GS} = 4.5V		0.0059	0.0068	Ω
r _{DS(ON)}		$I_D = 35A, V_{GS} = 10V,$ $T_1 = 175^{\circ}C$		-	0.0078	0.0094	Ω
Dynamic	Characteristics	Ū		1			
C _{ISS}	Input Capacitance	V _{DS} = 15V, V _{GS} = 0V, f = 1MHz		-	2525	-	pF
C _{OSS}	Output Capacitance			-	490	-	pF
C _{RSS}	Reverse Transfer Capacitance			-	300	-	pF
R _G	Gate Resistance	V _{GS} = 0.5V, f = 1MHz		-	2.3	-	Ω
Q _{g(TOT)}	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$		-	48	67	nC
Q _{g(5)}	Total Gate Charge at 5V	$V_{CS} = 0V$ to 5V		-	25	36	nC
Q _{g(TH)}	Threshold Gate Charge	$V_{ee} = 0V \text{ to } 1V$	$V_{DD} = 15V$	-	2.3	3.0	nC
Q _{gs}	Gate to Source Gate Charge		I _D = 35A I _a = 1.0mA	-	8	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau			-	5.7	-	nC
Q _{gd}	Gate to Drain "Miller" Charge			-	9.5	-	nC
Switching	g Characteristics (V _{GS} = 10V)						
t _{ON}	Turn-On Time			-	-	167	ns
t _{d(ON)}	Turn-On Delay Time	_		-	9	-	ns
t _r	Rise Time	$V_{DD} = 15V, I_D = 35A$ $V_{GS} = 4.5V, R_{GS} = 6.2\Omega$		-	102	-	ns
t _{d(OFF)}	Turn-Off Delay Time			-	58	-	ns
t _f	Fall Time			-	44	-	ns
t _{OFF}	Turn-Off Time			-	-	153	ns
Drain-So	urce Diode Characteristics						
V _{SD}	Source to Drain Diade Veltage	I _{SD} = 35A		-	-	1.25	V
	Source to Drain Diode Voltage	$I_{SD} = 20A$		-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$		-	-	27	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$		-	-	12	nC

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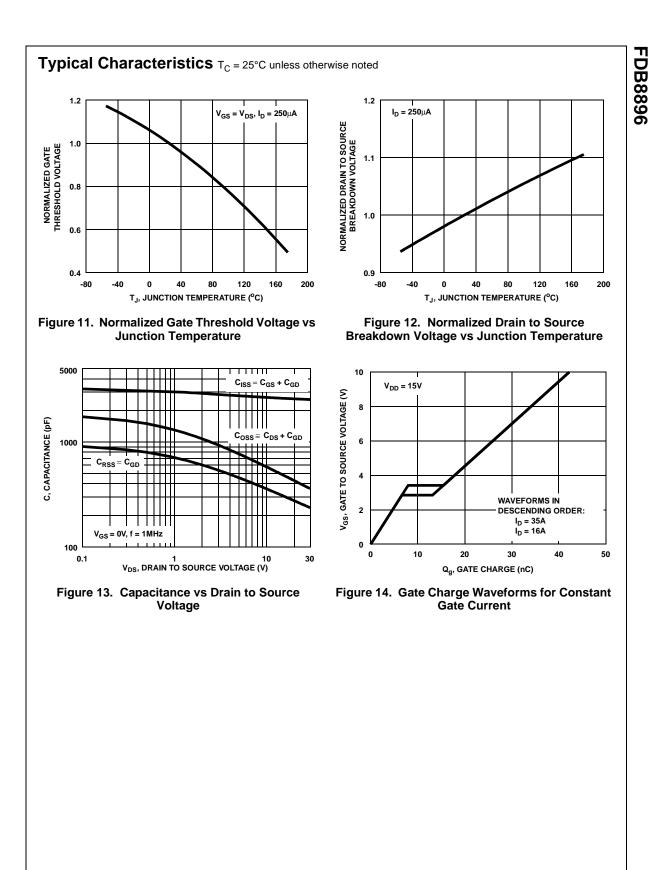


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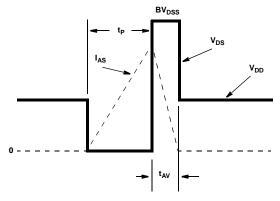


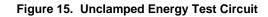
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FDB8896 Rev. B2



Test Circuits and Waveforms





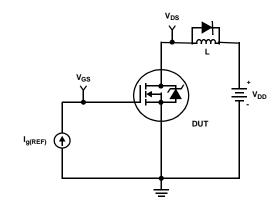


Figure 17. Gate Charge Test Circuit

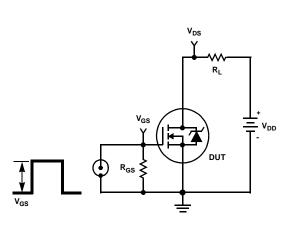


Figure 19. Switching Time Test Circuit

Figure 16. Unclamped Energy Waveforms

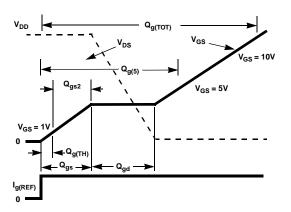
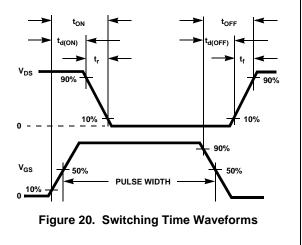


Figure 18. Gate Charge Waveforms



Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta,JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

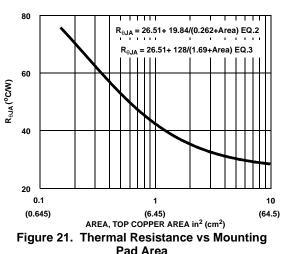
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

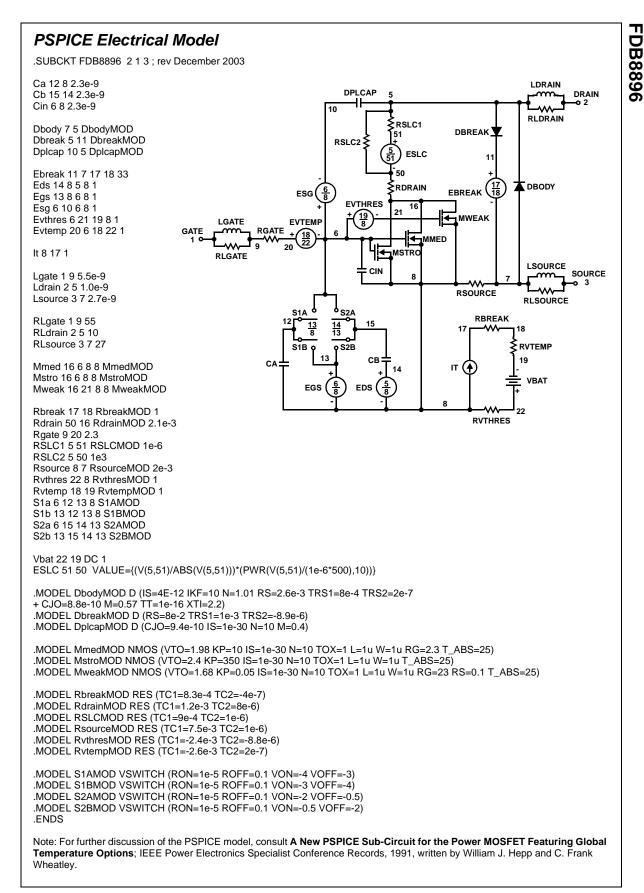
$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
 (EQ. 2)

Area in Inches Squared

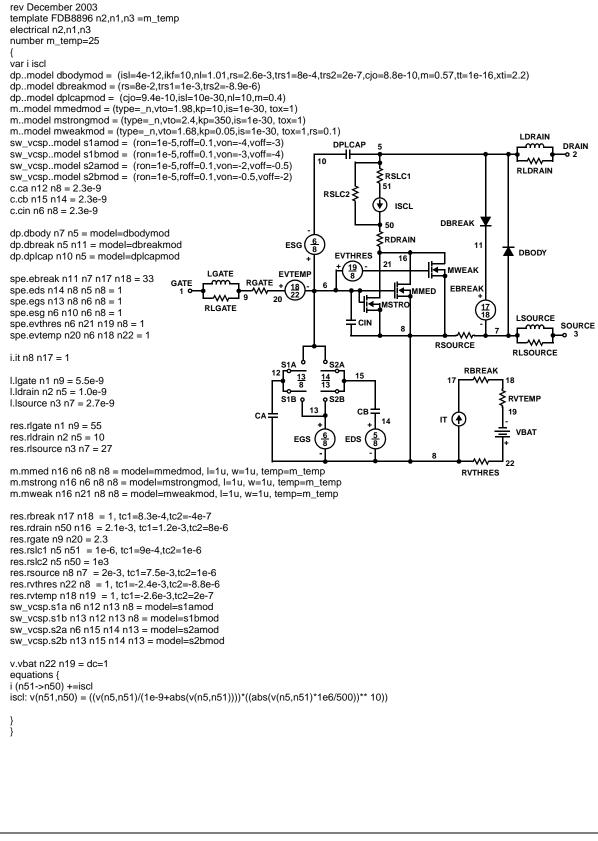
$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
(EQ. 3)

Area in Centimeters Squared

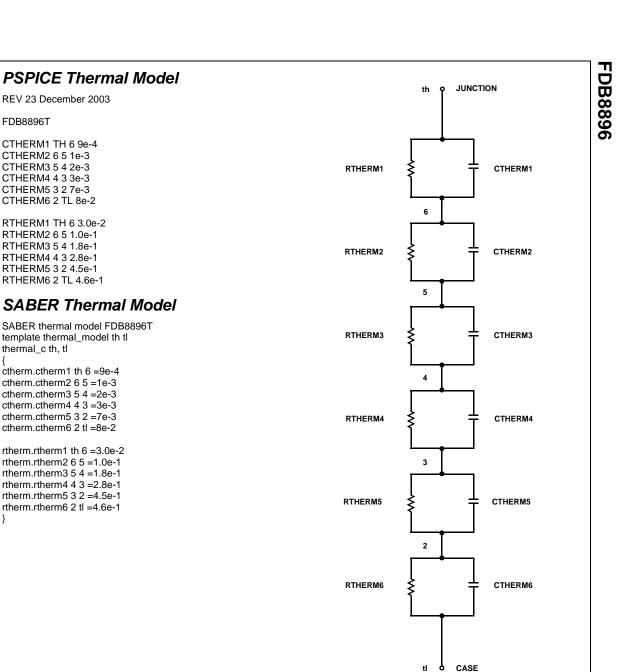




SABER Electrical Model



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